

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

APPLICANTS : **Jong-Cheol Lee, et al.** **ATTY DOCKET NO.** : 8836-223JHM/ID12244US
SERIAL NO. : 10/748,906 **EXAMINER** : Saqib Javaid Siddiqui
FILED : December 30, 2003 **ART UNIT** : 2138
TITLE : *SEMICONDUCTOR MEMORY DEVICE TESTABLE WITH A SINGLE DATA RATE AND/OR DUAL DATA RATE PATTERN IN A MERGED DATA INPUT/OUTPUT PIN TEST MODE*

MAIL STOP: AF
Commissioner for Patents
P.O. Box 1450
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AMENDMENT AFTER FINAL ACTION UNDER 37 CFR 1.116

S I R :

In response to the Official Action of July 10, 2007, applicants respectfully request that the above-identified application be amended as follows.

Amendments to the claims are reflected in the Listing of Claims that begins on page 2 of this Amendment.

The Remarks portion begins on page 6 of this Amendment.